

<b>Notice of References Cited</b>	Application/Control No. 10/505,299	Applicant(s)/Patent Under Reexamination WAUGH ET AL.	
	Examiner Abigail M. Cotton	Art Unit 1617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0009491	01-2002	Rothbard et al.	424/484
*	B	US-4,725,609	02-1988	Kull et al.	514/355
*	C	US-5,785,978	07-1998	Porter et al.	424/401
*	D	US-5,902,593	05-1999	Kent et al.	424/401
*	E	US-5,637,316	06-1997	Ribier et al.	424/450
*	F	US-4,933,172	06-1990	Clark et al.	424/49
*	G	US-5,891,459	04-1999	Cooke et al.	424/439
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Alison M. Layton, Optimal Management of Acne to Prevent Scarring and Psychological Sequelae, 2001, Am. J. Clin. Dermatol, 2(3), 135-141
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.